

Deutsche Akkreditierungsstelle GmbH

Annex to the Accreditation Certificate D-PL11140-03-02 according to DIN EN ISO/IEC 17025:2005

Period of validity: 16.03.2017 to 15.03.2022

Date of issue: 28.03.2017

Holder of certificate:

**Fraunhofer Gesellschaft zur Förderung der angewandten Forschung e.V.
Hansastraße 27 c, 80686 München**

with its test laboratories:

**Fraunhofer-Institut für Solare Energiesysteme (ISE)
TestLab PV Modules (TLPV)
Heidenhofstraße 2, 79110 Freiburg**

Tests in the fields:

Performance test of photovoltaic modules

Abbreviations used: see last page

The testing laboratory is permitted, without being required to inform and obtain prior approval from DAkkS, to use standards or equivalent testing methods listed here with different issue dates.

The testing laboratory maintains a current list of all testing methods within the flexible scope of accreditation.

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IEC 61215-1 Ed. 1 2016	Crystalline terrestrial photovoltaic (PV) modules - Design qualification and type approval Part 1: Test requirements
IEC 61215 Ed.2 2005	Crystalline silicon terrestrial photovoltaic (PV) modules - Design qualification and type approval
IEC 61215-1-1 Ed. 1 2016	Crystalline terrestrial photovoltaic modules - Design qualification and type approval Part 1-1: Special requirements for testing of crystalline silicon photovoltaic (PV) modules
IEC 61215-2 Ed. 1 2016	Crystalline terrestrial photovoltaic modules - Design qualification and type approval - Part 2: Test procedures
IEC 61646 Ed.2 2008	Thin-Film terrestrial photovoltaic (PV) modules - Design qualification and type approval
IEC 61730-1:2004 +AMD1:2001 +AMD2:2013	Photovoltaic (PV) module safety qualification - Part 2: Requirements for testing
IEC 61730-2:2004 +AMD1:2011	Photovoltaic (PV) module safety qualification - Part 2: Requirements for testing
IEC TS 62782 2016	Photovoltaic (PV) modules - Cyclic (dynamic) mechanical load testing
IEC TS 62804-1 2015	Photovoltaic (PV) modules - Test methods for the detection of potential-induced degradation - Part 1: Crystalline silicon

Abbreviations used:

IEC International Electrotechnical Commission